

# **Notice of References Cited**

Application/Control No.

09/901,079

Applicant(s)/Patent Under  
Reexamination  
LEE ET AL.

Examiner

Timothy L. Rude

Art Unit

2871

Pag 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,356,328	03-2002	Shin et al.	349/141
	B	US-6,163,355	12-2000	Chang et al.	349/141
	C	US-6,414,729	07-2002	Akiyama et al.	349/38
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-2000-111957	04-2000	Japan	Michiaki et al.	G02F
	O					
	P					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.